

RF Power Field Effect Transistor

N-Channel Enhancement-Mode Lateral MOSFET

Designed for W-CDMA base station applications with frequencies from 1930 to 1990 MHz. Suitable for TDMA, CDMA and multicarrier amplifier applications. To be used in Class AB for PCN-PCS/cellular radio and WLL applications.

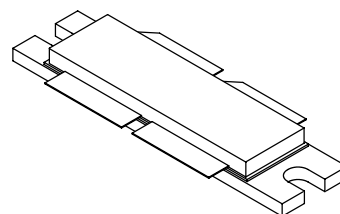
- Typical 2-Carrier W-CDMA Performance: $V_{DD} = 28$ Volts, $I_{DQ} = 1600$ mA, $P_{out} = 38$ Watts Avg., $f = 1977.5$ MHz, Channel Bandwidth = 3.84 MHz, PAR = 8.5 dB @ 0.01% Probability on CCDF.
Power Gain — 14 dB
Drain Efficiency — 26%
IM3 @ 10 MHz Offset — -37.5 dBc in 3.84 MHz Channel Bandwidth
ACPR @ 5 MHz Offset — -41 dBc in 3.84 MHz Channel Bandwidth
- Capable of Handling 10:1 VSWR, @ 28 Vdc, 1960 MHz, 120 Watts CW Output Power

Features

- Characterized with Series Equivalent Large-Signal Impedance Parameters
- Internally Matched for Ease of Use
- Qualified Up to a Maximum of 32 V_{DD} Operation
- Integrated ESD Protection
- Lower Thermal Resistance Package
- Low Gold Plating Thickness on Leads, 40 μ ” Nominal.
- RoHS Compliant
- In Tape and Reel. R6 Suffix = 150 Units per 56 mm, 13 inch Reel.

MRF5P20180HR6

1930-1990 MHz, 38 W AVG., 28 V
2 x W-CDMA
LATERAL N-CHANNEL
RF POWER MOSFET



CASE 375D-05, STYLE 1
NI-1230

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Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	-0.5, +65	Vdc
Gate-Source Voltage	V_{GS}	-0.5, +15	Vdc
Total Device Dissipation @ $T_C = 25^\circ\text{C}$ Derate above 25 $^\circ\text{C}$	P_D	530 3.0	W W/ $^\circ\text{C}$
Storage Temperature Range	T_{stg}	- 65 to +150	$^\circ\text{C}$
Case Operating Temperature	T_C	150	$^\circ\text{C}$
Operating Junction Temperature	T_J	200	$^\circ\text{C}$
CW Operation @ $T_C = 25^\circ\text{C}$ Derate above 25 $^\circ\text{C}$	CW	185 1.2	W W/ $^\circ\text{C}$

Table 2. Thermal Characteristics

Characteristic	Symbol	Value (1,2)	Unit
Thermal Resistance, Junction to Case Case Temperature 77 $^\circ\text{C}$, 120 W CW Case Temperature 72 $^\circ\text{C}$, 38 W CW	$R_{\theta JC}$	0.33 0.35	$^\circ\text{C}/\text{W}$

1. MTF calculator available at <http://www.freescale.com/rf>. Select Software & Tools/Development Tools/Calculators to access MTF calculators by product.
2. Refer to AN1955, *Thermal Measurement Methodology of RF Power Amplifiers*. Go to <http://www.freescale.com/rf>. Select Documentation/Application Notes - AN1955.

Table 3. ESD Protection Characteristics

Test Conditions	Class
Human Body Model	2 (Minimum)
Machine Model	M3 (Minimum)
Charge Device Model	C7 (Minimum)

Table 4. Electrical Characteristics ($T_C = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
Off Characteristics ⁽¹⁾					
Zero Gate Voltage Drain Leakage Current ($V_{DS} = 65\text{ Vdc}$, $V_{GS} = 0\text{ Vdc}$)	I_{DSS}	—	—	10	μAdc
Zero Gate Voltage Drain Leakage Current ($V_{DS} = 28\text{ Vdc}$, $V_{GS} = 0$)	I_{DSS}	—	—	1	μAdc
Gate-Source Leakage Current ($V_{GS} = 5\text{ Vdc}$, $V_{DS} = 0\text{ Vdc}$)	I_{GSS}	—	—	1	μAdc

On Characteristics

Gate Threshold Voltage ⁽¹⁾ ($V_{DS} = 10\text{ Vdc}$, $I_D = 200\ \mu\text{Adc}$)	$V_{GS(th)}$	2.5	2.7	3.5	Vdc
Gate Quiescent Voltage ⁽³⁾ ($V_{DS} = 28\text{ Vdc}$, $I_D = 1600\text{ mAdc}$)	$V_{GS(Q)}$	—	3.6	—	Vdc
Drain-Source On-Voltage ⁽¹⁾ ($V_{GS} = 10\text{ Vdc}$, $I_D = 2\text{ Adc}$)	$V_{DS(on)}$	—	0.26	0.3	Vdc
Forward Transconductance ⁽¹⁾ ($V_{DS} = 10\text{ Vdc}$, $I_D = 2\text{ Adc}$)	g_{fs}	—	5	—	S

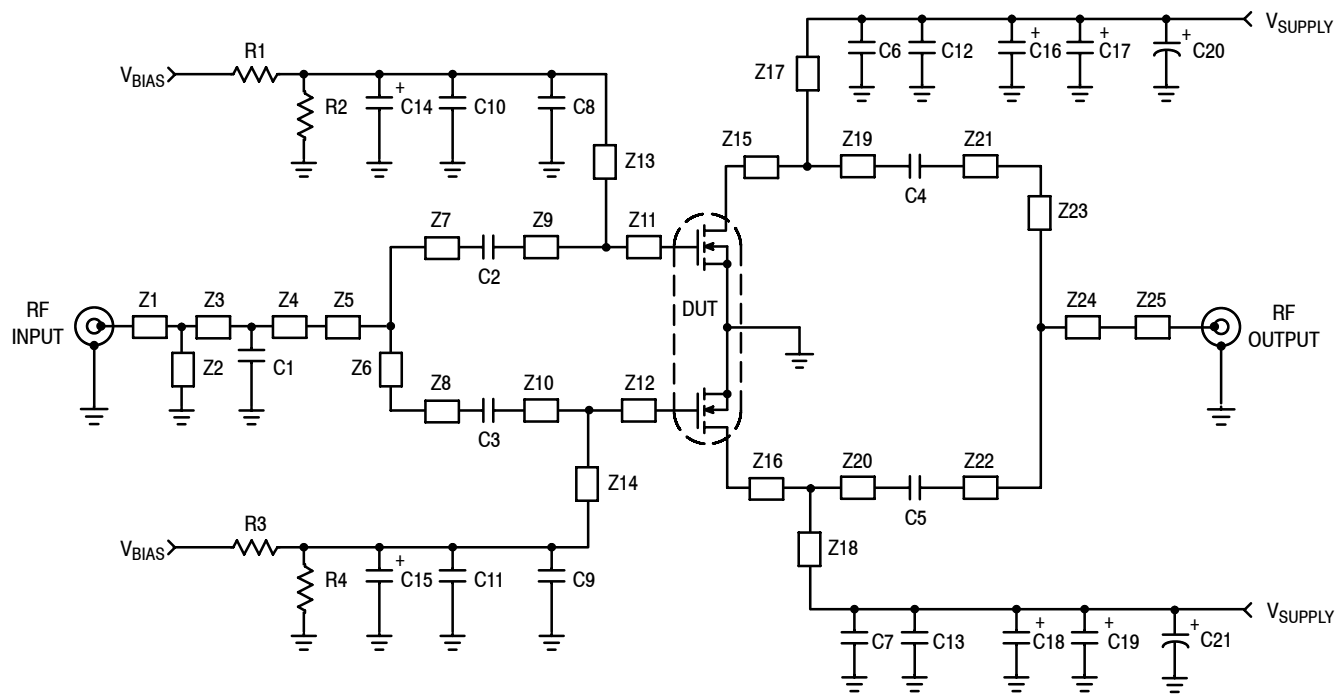
Dynamic Characteristics ^(1,2)

Reverse Transfer Capacitance ($V_{DS} = 28\text{ Vdc} \pm 30\text{ mV(rms)ac}$ @ 1 MHz, $V_{GS} = 0\text{ Vdc}$)	C_{rss}	—	1.7	—	pF
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Functional Tests ⁽³⁾ (In Freescale Test Fixture, 50 ohm system) $V_{DD} = 28\text{ Vdc}$, $I_{DQ} = 1600\text{ mA}$, $P_{out} = 38\text{ W Avg.}$, $f_1 = 1977.5\text{ MHz}$, $f_2 = 1987.5\text{ MHz}$, 2-Carrier W-CDMA, 3.84 MHz Channel Bandwidth Carriers. ACPR measured in 3.84 MHz Channel Bandwidth @ $\pm 5\text{ MHz}$ Offset. IM3 measured in 3.84 MHz Bandwidth @ $\pm 10\text{ MHz}$ Offset. PAR = 8.5 dB @ 0.01% Probability on CCDF.

Power Gain	G_{ps}	12.5	14	—	dB
Drain Efficiency	η_D	23	26	—	%
Intermodulation Distortion	IM3	—	-37.5	-35	dBc
Adjacent Channel Power Ratio	ACPR	—	-41	-38	dBc
Input Return Loss	IRL	—	-16	-9	dB

- Each side of device measured separately.
- Part internally matched both on input and output.
- Measurement made with device in push-pull configuration.

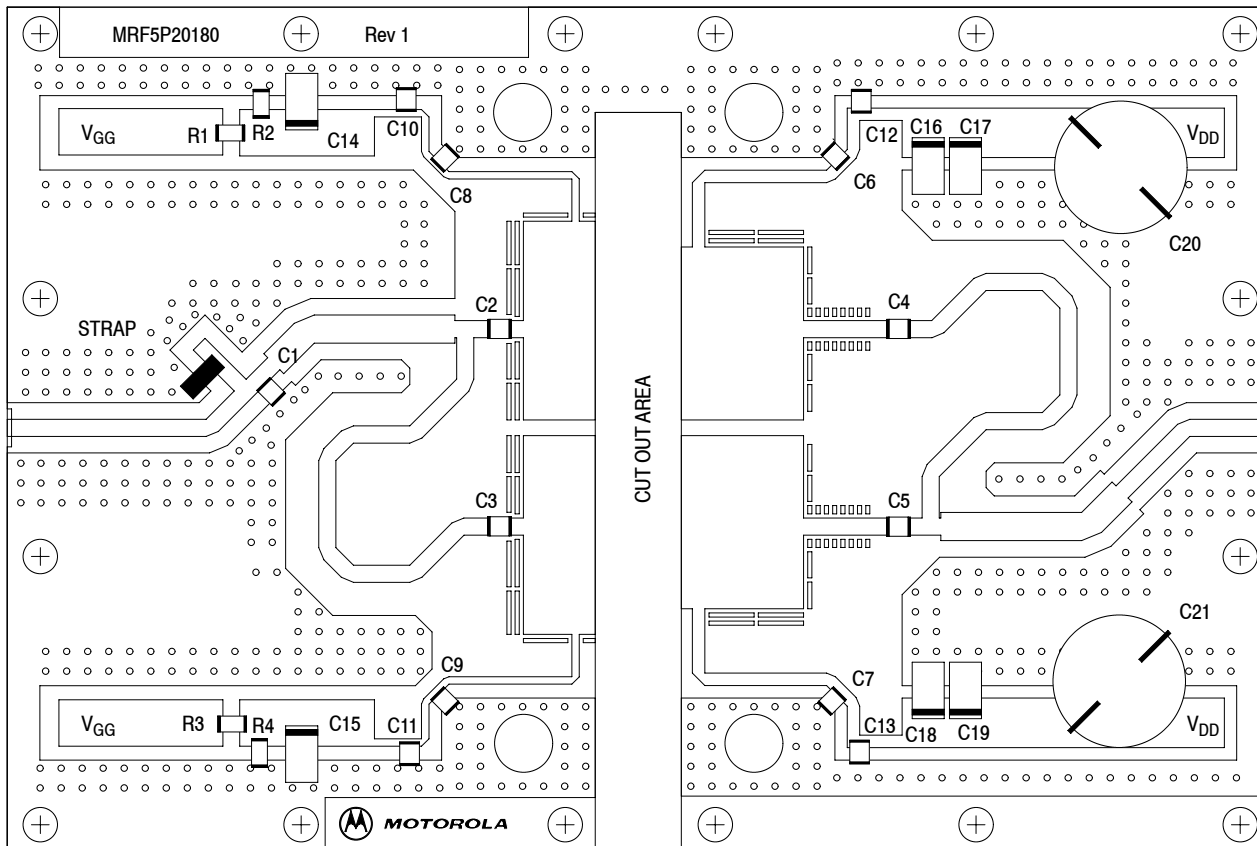


Z1	0.081" x 1.126" Microstrip	Z11, Z12	0.341" x 0.945" Microstrip
Z2	0.079" x 0.138" Microstrip	Z13, Z14	0.035" x 0.913" Microstrip
Z3	0.081" x 0.091" Microstrip	Z15, Z16	0.581" x 0.823" Microstrip
Z4	0.081" x 0.117" Microstrip	Z17, Z18	0.059" x 1.057" Microstrip
Z5, Z24	0.134" x 0.874" Microstrip	Z19, Z20	0.081" x 0.046" Microstrip
Z6, Z23	0.081" x 2.269" Microstrip	Z21, Z22	0.081" x 0.126" Microstrip
Z7, Z8	0.081" x 0.118" Microstrip	Z25	0.081" x 0.793" Microstrip
Z9, Z10	0.081" x 0.079" Microstrip	PCB	Taconic TLX8-0300, 0.030", $\epsilon_r = 2.55$

Figure 1. MRF5P20180HR6 Test Circuit Schematic

Table 5. MRF5P20180HR6 Test Circuit Component Designations and Values

Part	Description	Part Number	Manufacturer
C1	1.8 pF 100B Chip Capacitor	ATC100B1R8BT500XT	ATC
C2, C3, C4, C5, C6, C7	10 pF 100B Chip Capacitors	ATC100B100GT500XT	ATC
C8, C9	6.8 pF 100B Chip Capacitors	ATC100B6R8CT500XT	ATC
C10, C11, C12, C13	10 nF 200B Chip Capacitors	ATC200B103MT500XT	ATC
C14, C15, C16, C17, C18, C19	22 μ F, 35 V Tantalum Capacitors	TAJE226M035S	AVX
C20, C21	220 μ F, 63 V Electrolytic Capacitors	EMVY630GTR221MLH0S	Nippon Chemi-Con
R1, R2, R3, R4	10 k Ω , 1/4 W Chip Resistors	CRCW12061002FKEA	Vishay



Freescall has begun the transition of marking Printed Circuit Boards (PCBs) with the Freescall Semiconductor signature/logo. PCBs may have either Motorola or Freescall markings during the transition period. These changes will have no impact on form, fit or function of the current product.

Figure 2. MRF5P20180HR6 Test Circuit Component Layout

TYPICAL CHARACTERISTICS

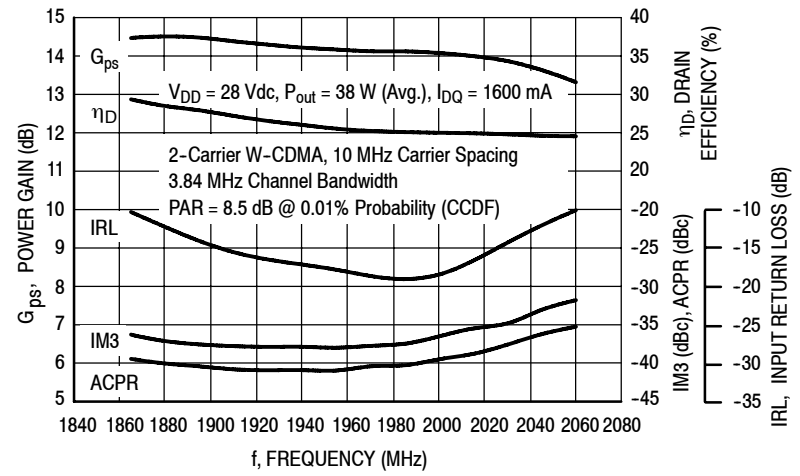


Figure 3. 2-Carrier W-CDMA Broadband Performance @ P_{out} = 38 Watts Avg.

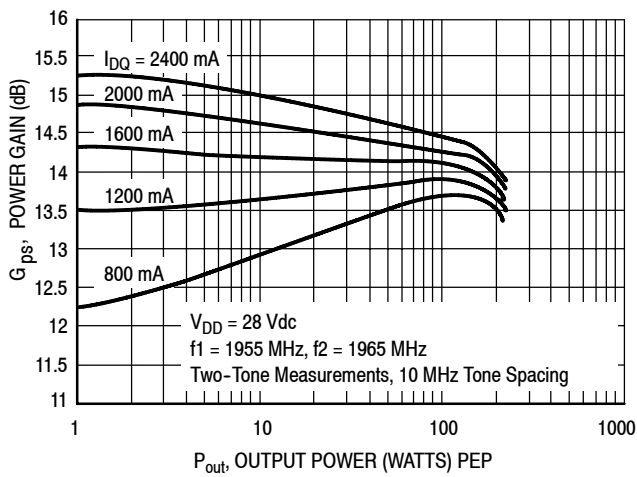


Figure 4. Two-Tone Power Gain versus Output Power

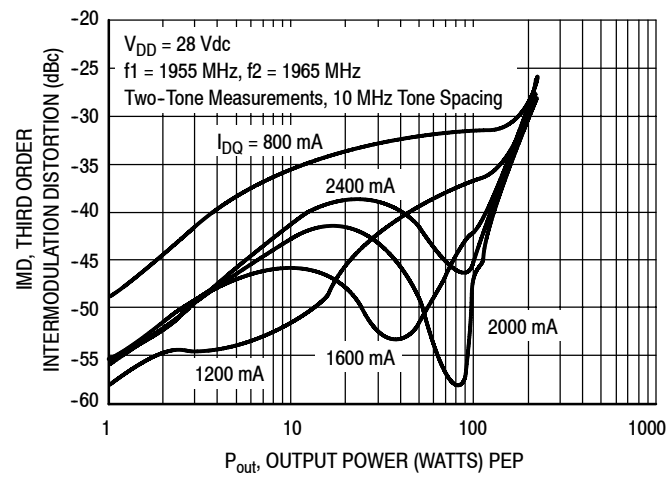


Figure 5. Third Order Intermodulation Distortion versus Output Power

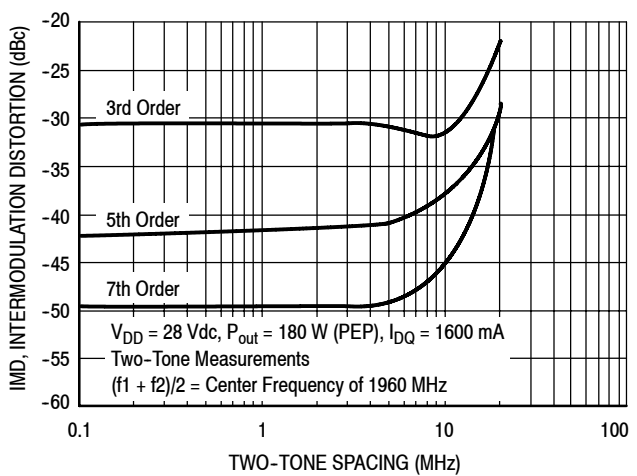


Figure 6. Intermodulation Distortion Products versus Tone Spacing

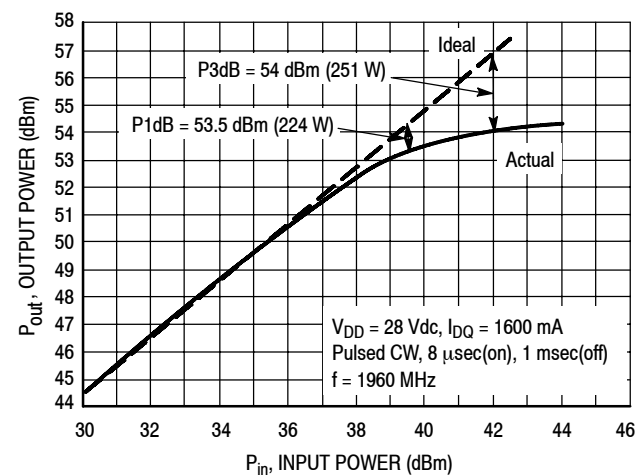


Figure 7. Pulse CW Output Power versus Input Power

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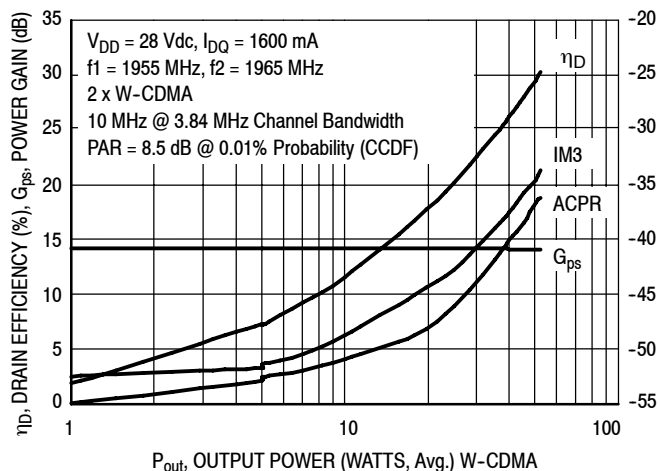
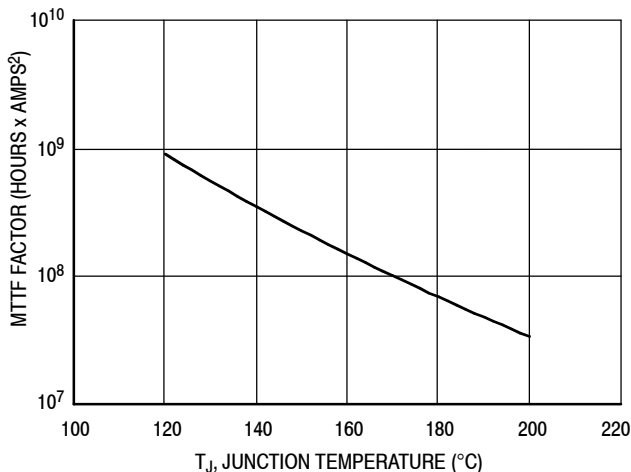


Figure 8. 2-Carrier W-CDMA ACPR, IM3, Power Gain and Drain Efficiency versus Output Power



This above graph displays calculated MTTF in hours x ampere² drain current. Life tests at elevated temperatures have correlated to better than $\pm 10\%$ of the theoretical prediction for metal failure. Divide MTTF factor by I_D^2 for MTTF in a particular application.

Figure 9. MTTF Factor versus Junction Temperature

W-CDMA TEST SIGNAL

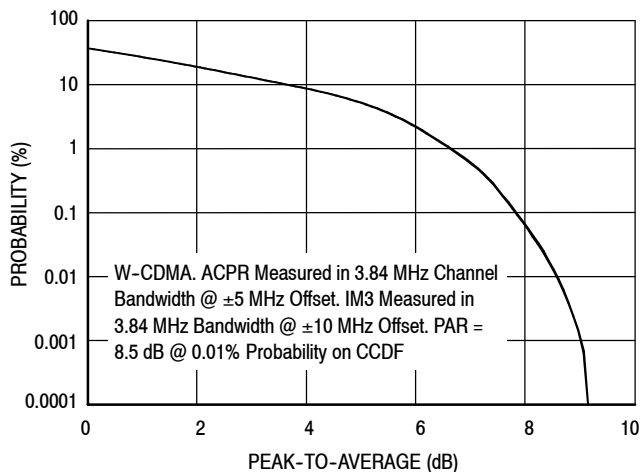


Figure 10. CCDF W-CDMA 3GPP, Test Model 1, 64 DPCH, 67% Clipping, Single Carrier Test Signal

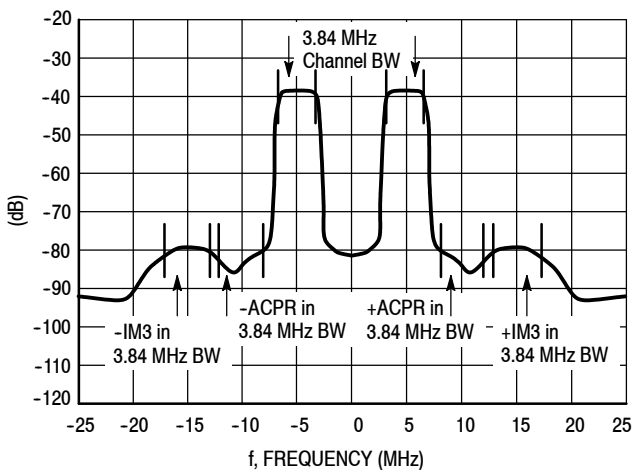
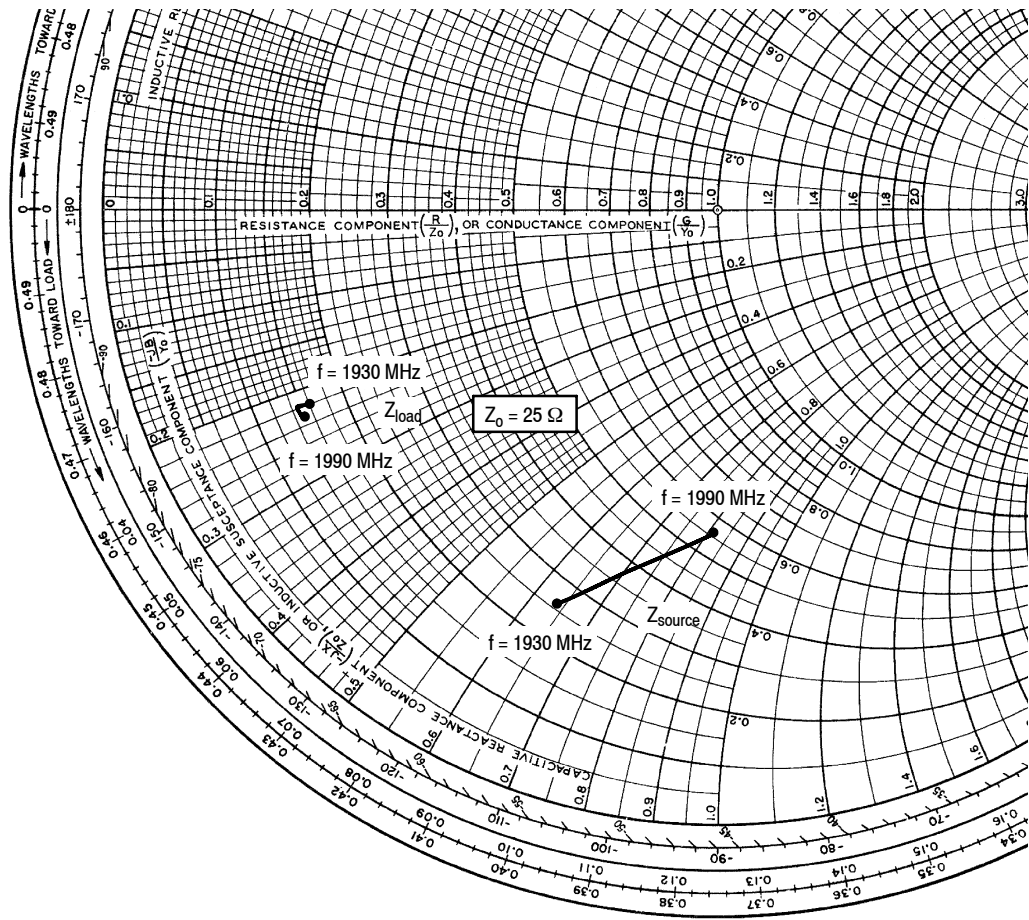


Figure 11. 2-Carrier W-CDMA Spectrum



$V_{DD} = 28$ V, $I_{DQ} = 1600$ mA, $P_{out} = 38$ W Avg.

f MHz	Z_{source} Ω	Z_{load} Ω
1930	$6.54 - j16.04$	$4.06 - j5.56$
1960	$9.70 - j17.92$	$3.70 - j5.48$
1990	$13.88 - j20.46$	$3.64 - j5.76$

Z_{source} = Test circuit impedance as measured from gate to gate, balanced configuration.

Z_{load} = Test circuit impedance as measured from drain to drain, balanced configuration.

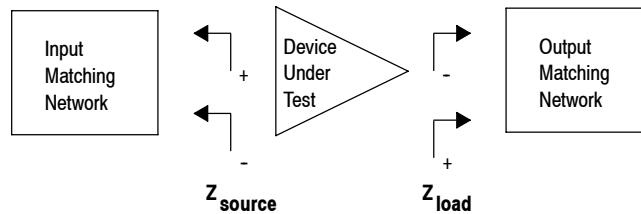


Figure 12. Series Equivalent Source and Load Impedance

REVISION HISTORY

The following table summarizes revisions to this document.

Revision	Date	Description
2	Oct. 2008	<ul style="list-style-type: none"> • Modified data sheet to reflect RF Test Reduction described in Product and Process Change Notification number, PCN12779, p. 1, 2 • Updated Part Numbers in Table 5, Component Designations and Values, to RoHS compliant part numbers, p. 3 • Added Revision History, p. 9 • Data sheet archived. Part no longer manufactured.

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